Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/645,602	SHEU ET AL.	
Examiner	Art Unit	
Frank W. Lu	1634	

	SEARCHED					
Class	Subclass	Date	Examiner			
435	6 91.1 183 94	1/6/w6	n			
436	94	•				
436 536	23.1 24.3 25.3					
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
STN	DATE	EXMR			
STN  East  (see attached file)  Inventor searche	\$/16/2006	n			